

<b>Notice of References Cited</b>	Application/Control No. 10/615,784	Applicant(s)/Patent Under Reexamination KIMURA ET AL.	
	Examiner David W. Scheuermann	Art Unit 2834	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,566,779	05-2003	Takano et al.	310/214
	B	US-			
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	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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